

Notice of References Cited	Application/Control No. 10/512,017		Applicant(s)/Patent Under Reexamination BENETIK ET AL.	
	Examiner Tsz K. Chiu		Art Unit 2822	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0161091	08-2003	Devoe et al.	361/321.2
*	B	US-6,366,443	04-2002	Devoe et al.	361/313
	C	US-			
	D	US-			
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	I	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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